

# Florian F Krause

## List of Publications by Year in descending order

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27  
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623734

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526287

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docs citations

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times ranked

916  
citing authors

#	ARTICLE	IF	CITATIONS
1	Towards the interpretation of a shift of the central beam in nano-beam electron diffraction as a change in mean inner potential. Ultramicroscopy, 2022, 236, 113503.	1.9	6
2	Angle-dependence of ADF-STEM intensities for chemical analysis of InGaN/GaN. Ultramicroscopy, 2022, 238, 113535.	1.9	4
3	Angle-resolved STEM using an iris aperture: Scattering contributions and sources of error for the quantitative analysis in Si. Ultramicroscopy, 2021, 221, 113175.	1.9	8
4	Accurate measurement of strain at interfaces in 4D-STEM: A comparison of various methods. Ultramicroscopy, 2021, 221, 113196.	1.9	10
5	Precise measurement of the electron beam current in a TEM. Ultramicroscopy, 2021, 223, 113221.	1.9	8
6	Accuracy and precision of position determination in ISTEM imaging of BaTiO <sub>3</sub> . Ultramicroscopy, 2021, 227, 113325.	1.9	2
7	4D-STEM at interfaces to GaN: Centre-of-mass approach & NBED-disc detection. Ultramicroscopy, 2021, 228, 113321.	1.9	9
8	Influence of plasmon excitations on atomic-resolution quantitative 4D scanning transmission electron microscopy. Scientific Reports, 2020, 10, 17890.	3.3	21
9	Comparison of first moment STEM with conventional differential phase contrast and the dependence on electron dose. Ultramicroscopy, 2019, 203, 95-104.	1.9	29
10	Influence of distortions of recorded diffraction patterns on strain analysis by nano-beam electron diffraction. Ultramicroscopy, 2019, 196, 74-82.	1.9	15
11	Using molecular dynamics for multislice TEM simulation of thermal diffuse scattering in AlGaN. Ultramicroscopy, 2018, 189, 124-135.	1.9	16
12	Quantitative HAADF STEM of SiGe in presence of amorphous surface layers from FIB preparation. Ultramicroscopy, 2018, 184, 29-36.	1.9	17
13	Measurement of local crystal lattice strain variations in dealloyed nanoporous gold. Materials Research Letters, 2018, 6, 84-92.	8.7	10
14	Strain analysis from nano-beam electron diffraction: Influence of specimen tilt and beam convergence. Ultramicroscopy, 2018, 190, 45-57.	1.9	17
15	Optimization of NBED simulations for disc-detection measurements. Ultramicroscopy, 2017, 181, 50-60.	1.9	13
16	Imaging theory for the ISTEM imaging mode. Ultramicroscopy, 2017, 181, 107-116.	1.9	5
17	Measurement of atomic electric fields and charge densities from average momentum transfers using scanning transmission electron microscopy. Ultramicroscopy, 2017, 178, 62-80.	1.9	106
18	Reciprocity relations in transmission electron microscopy: A rigorous derivation. Micron, 2017, 92, 1-5.	2.2	6

#	ARTICLE	IF	CITATIONS
19	Nanoscope Insights into InGaN/GaN Core-Shell Nanorods: Structure, Composition, and Luminescence. Nano Letters, 2016, 16, 5340-5346.	9.1	43
20	Materials characterisation by angle-resolved scanning transmission electron microscopy. Scientific Reports, 2016, 6, 37146.	3.3	33
21	Effects of instrument imperfections on quantitative scanning transmission electron microscopy. Ultramicroscopy, 2016, 161, 146-160.	1.9	55
22	Homogeneity and composition of AlInGaN: A multiprobe nanostructure study. Ultramicroscopy, 2015, 156, 29-36.	1.9	14
23	Theoretical study of precision and accuracy of strain analysis by nano-beam electron diffraction. Ultramicroscopy, 2015, 158, 38-48.	1.9	43
24	Atomic electric fields revealed by a quantum mechanical approach to electron picodiffraction. Nature Communications, 2014, 5, 5653.	12.8	232
25	Conventional Transmission Electron Microscopy Imaging beyond the Diffraction and Information Limits. Physical Review Letters, 2014, 113, 096101.	7.8	21
26	Influence of Static Atomic Displacements on Composition Quantification of AlGaIn/GaN Heterostructures from HAADF-STEM Images. Microscopy and Microanalysis, 2014, 20, 1463-1470.	0.4	11
27	Comparison of intensity and absolute contrast of simulated and experimental high-resolution transmission electron microscopy images for different multislice simulation methods. Ultramicroscopy, 2013, 134, 94-101.	1.9	25